




## KOREA SPECTRAL PRODUCTS

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major business	Spectrometer manufacture and sales		

Since its establishment in 2003, Korea Spectral Products(KSP) has been providing customized optical sensing systems to the world's leading semiconductor and sensor companies through a variety of spectrometers, optical accessories, and special OEM designed optical system. As a leading materials and components company in the optical measurement market, we are working with academia to promote the widespread use of optical diagnostics

### Products

 <p>SM245N&amp;SM642N&amp; SM303N Spectrometer</p>	<p><b>Use</b> Network-based multi-channel real-time plasma process diagnosis(Optical Emission Spectroscopy&amp;End Point Detection, etc.)</p> <p><b>Description</b> Process monitoring, self-calculation and diagnostic actors provided Remote OES data transfer without using a controller Simultaneous operation of more than 10 channel spectrometers Very low failure rate and automatic reconnection</p>
 <p>SM304 Spectrometer</p>	<p><b>Use</b> NIR Spectroscopy for component analysis, high thickness film measurement, and real-time gas monitoring</p> <p><b>Description</b> Provides information for OES diagnosis in extended wavelength band up to 2.5 um Used for a long time without affecting the viewport cloud effect Component monitoring for various chemical species and films Measurement of film properties for high thickness film. Used as a spectral sensor for SE/SR measurement</p>
 <p>SM301 Spectrometer</p>	<p><b>Use</b> Realtime Monitoring of the MWIR spectrum</p> <p><b>Description</b> The simplest spectroscopic system that can measure up to MWIR Applications – Infrared laser/environmental/medical/food/pharmaceutical/product manufacturing/defense/aviation</p>

### Technical Capacity

#### » Semiconductor&Display Manufacturing Process Diagnostics&Monitoring

Semiconductor/display process monitoring and diagnosis system(OES system) technology, it is possible to detect leakage in real time due to inflow of outside air. Plasma principal factors(PI) such as gas temperature, electron temperature and electron density can be analyzed

#### » Material Analysis

A variety of materials can be analyzed, including Raman and fluorescence/phosphorescence(PL) analysis, and refractive index analysis using ellipsometry

#### » Biomedical&Environmental

High-speed single/multi-channel blood test and diagnosis system using component test and condition diagnosis technology. Near-infrared spectrophotometer-based liquid fertilizer component analyzer(liquid sample analysis possible)